## **VE 320 Summer 2019**

#### Introduction to Semiconductor Devices

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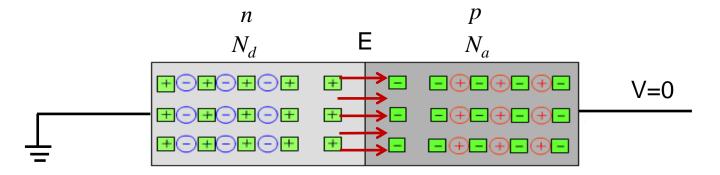
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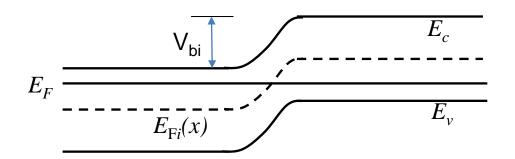


# Lecture 8

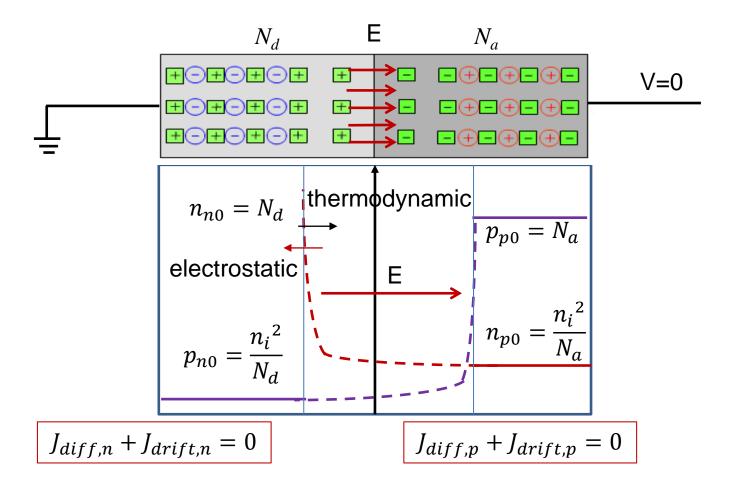
pn junction diode (Chapter 8)

charge carrier transport: <u>zero bias</u>

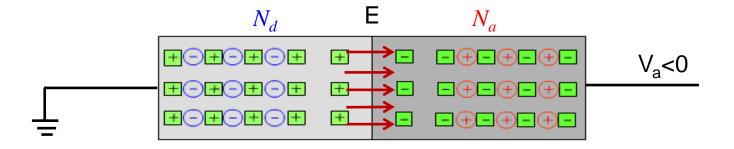


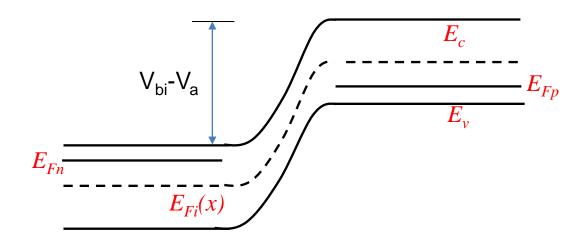


charge carrier transport: <u>zero bias</u>

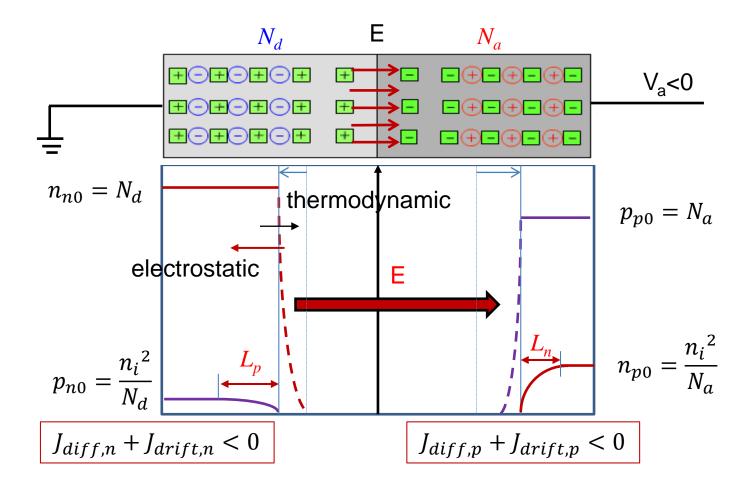


• charge carrier transport: reverse bias

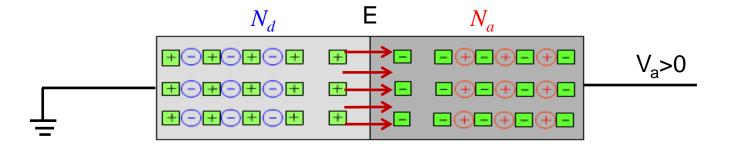


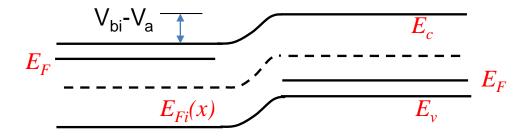


charge carrier transport: <u>reverse bias</u>

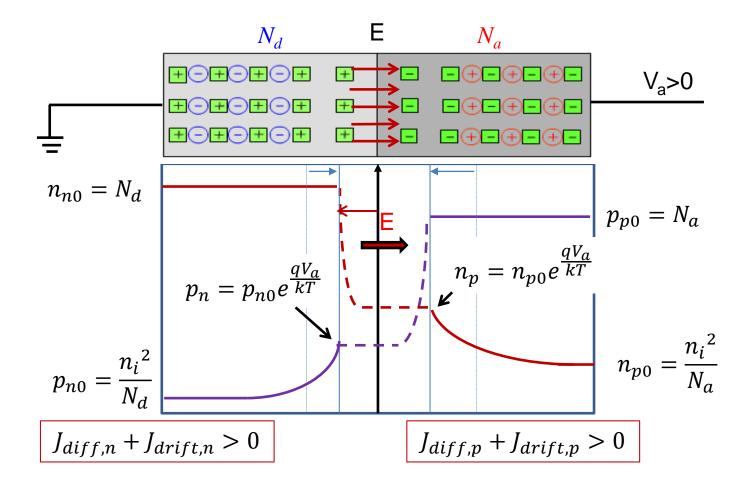


• charge carrier transport: forward bias



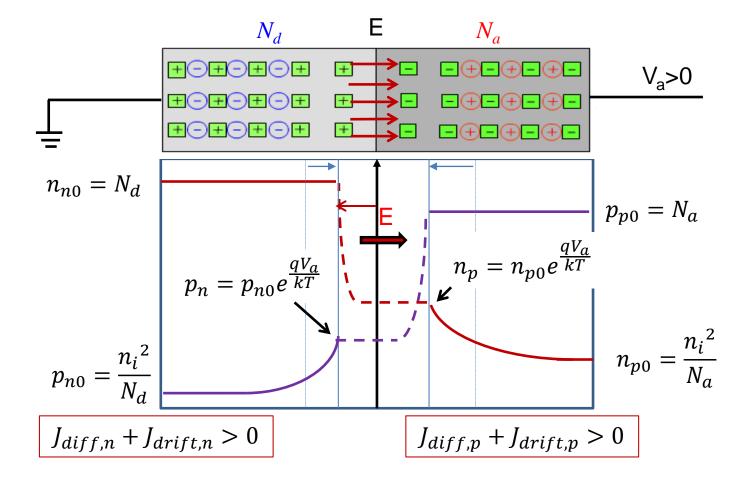


charge carrier transport: <u>forward bias</u>



charge carrier transport: <u>forward bias</u>

Electric field is reduced
Diffusion current
Minority carrier injection:
nonequilibium excess carriers!



#### Ideal *I-V* relationship assumption:

- Abrupt depletion layer approximation: The space charge regions have abrupt boundaries, and the semiconductor is neutral outside of the depletion region
- Boltzmann approximation applies to carrier statistics
- Low injection and complete ionization apply
- Current:
  - The total current is a constant throughout the entire pn structure
  - The individual electron and hole currents are continuous functions through the pn structure
  - The individual electron and hole currents are constant throughout the depletion region



Minority carrier concentration:

Previously we have

$$V_{bi} = V_t \ln \left( \frac{N_a N_d}{n_i^2} \right) \qquad V_t = kT/e$$

Then 
$$\frac{n_i^2}{N_a N_d} = \exp\left(\frac{-eV_{bi}}{kT}\right)$$

Then  $\frac{n_i^2}{N_a N_d} = \exp\left(\frac{-eV_{bi}}{kT}\right)$  Complete ionization:  $n_{n0} \approx N_d$   $n_{p0} \approx \frac{n_i^2}{N}$ 

So 
$$n_{p0} = n_{n0} \exp\left(\frac{-eV_{bi}}{kT}\right)$$

So  $n_{p0}=n_{n0}\exp\left(rac{-eV_{bi}}{kT}
ight)$  relates the minority carrier on the p side to the majority carrier electron concentration on the n side in thermal equilibrium

Forward-biased pn junction: bias  $V_a$ 

$$n_p = n_{n0} \exp\left(\frac{-e(V_{bi} - V_a)}{kT}\right) = n_{n0} \exp\left(\frac{-eV_{bi}}{kT}\right) \exp\left(\frac{+eV_a}{kT}\right)$$

$$n_p = n_{p0} \exp\left(\frac{eV_a}{kT}\right)$$

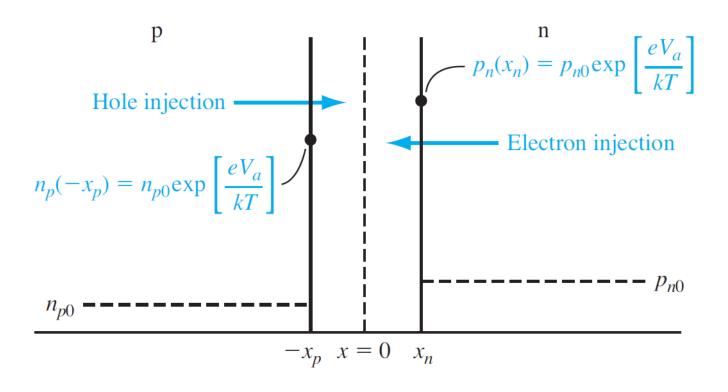
 $n_p = n_{p0} \exp\left(\frac{eV_a}{kT}\right)$  Forward-bias: no longer in thermal equilibrium Exponential change, excess minority carriers

Concentration at the edge

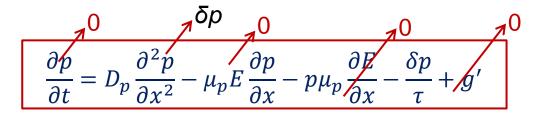
Similarly, for holes in n-region:

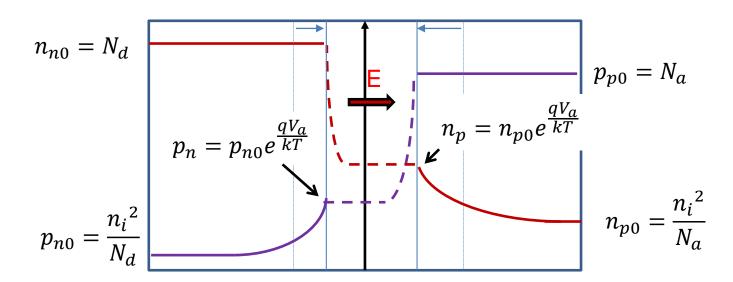
$$p_n = p_{n0} \exp\left(\frac{eV_a}{kT}\right)$$

Consider Forward-biased pn junction: bias  $V_a$ 



- charge carrier transport: forward bias
- In the n-region: E=0, and g'=0





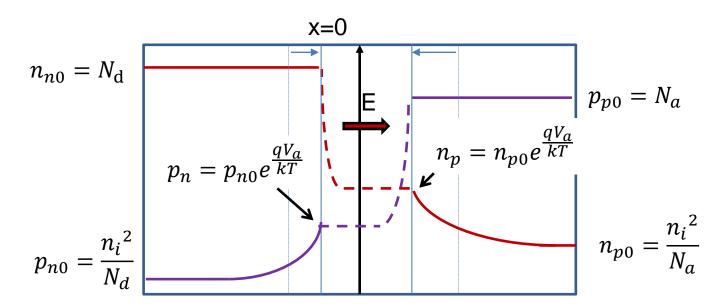
charge carrier transport: forward bias n-region

$$D_p \frac{\partial^2 \delta p}{\partial x^2} - \frac{\delta p}{\tau} = 0$$

$$D_{p} \frac{\partial^{2} \delta p}{\partial x^{2}} - \frac{\delta p}{\tau} = 0 \qquad \frac{d^{2} (\delta p_{n})}{dx^{2}} - \frac{\delta p_{n}}{L_{p}^{2}} = 0$$

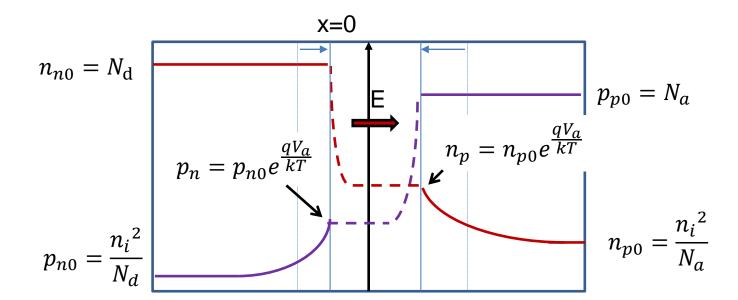
$$L_p^2 = D_p \, au_{p0}$$

$$\Rightarrow \delta p_n(x) = p_n(x) - p_{n0} = Ae^{-x/L_p} + Be^{x/L_p}$$



charge carrier transport: <u>forward bias</u>
 Similarly, p-region

$$\frac{d^{2}(\delta n_{p})}{dx^{2}} - \frac{\delta n_{p}}{L_{n}^{2}} = 0 \qquad \qquad L_{n}^{2} = D_{n} \tau_{n0}$$
$$\delta n_{p}(x) = n_{p}(x) - n_{p0} = Ce^{x/L_{n}} + De^{-x/L_{n}}$$



charge carrier transport: <u>forward bias</u>

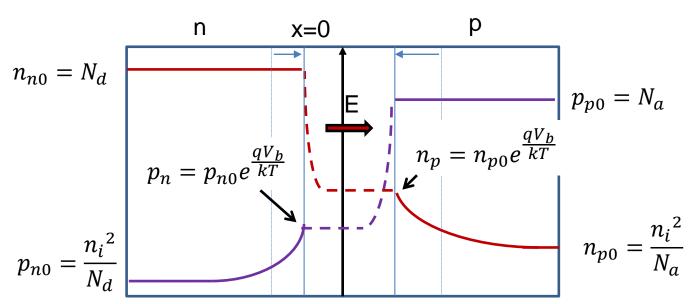
Boundary conditions:

• 
$$p_n(-x_n) = p_{n0} \exp(\frac{eVa}{kT}), \quad n_p(x_p) = n_{p0} \exp(\frac{eVa}{kT})$$

• 
$$p_n(x \to -\infty) = p_{n0}$$
,  $n_p(x \to \infty) = n_{p0}$ 

Or:  $\delta p$  must be close to 0 deep into the n region (long pn junction): recombination  $\delta n$  must be close to 0 deep into the p region (long pn junction): recombination

n-region: 
$$\Rightarrow \delta p_n(x) = p_n(x) - p_{n0} = p_{n0}(e^{\frac{eV_a}{kT}} - 1)e^{(x+x_n)/L_p}$$



n on the left, p on the right

charge carrier transport: forward bias

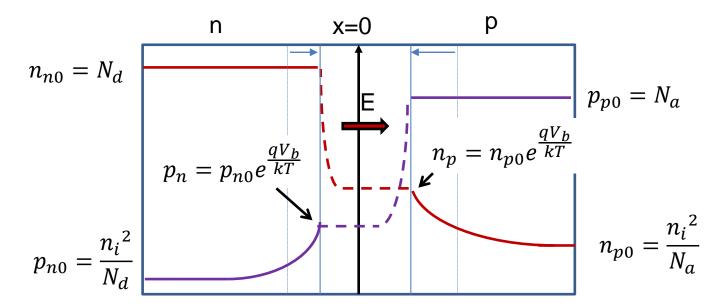
#### Boundary conditions:

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Or:  $\delta p$  must be close to 0 deep into the n region (long pn junction): recombination  $\delta n$  must be close to 0 deep into the p region (long pn junction): recombination

p-region: 
$$\Rightarrow \delta n_p(x) = n_p(x) - n_{p0} = n_{p0} (e^{\frac{eV_a}{kT}} - 1) e^{(x_p - x)/L_n}$$

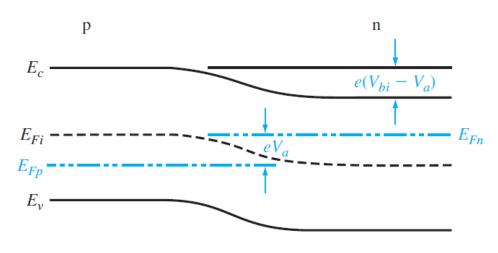


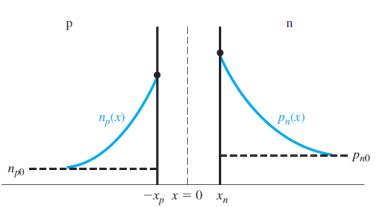
#### n on the right, p on the left

charge carrier transport: <u>forward bias</u>

n-region 
$$(x \ge x_n)$$
:  $\delta p_n(x) = p_n(x) - p_{n0} = p_{n0} \left[ \exp\left(\frac{eV_a}{kT}\right) - 1 \right] \exp\left(\frac{x_n - x}{L_p}\right)$ 

p-region 
$$(x \le -x_p)$$
:  $\delta n_p(x) = n_p(x) - n_{p0} = n_{p0} \left[ \exp\left(\frac{eV_a}{kT}\right) - 1 \right] \exp\left(\frac{x_p + x}{L_n}\right)$ 





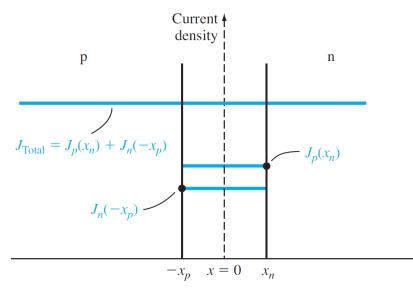
- Assumption: No generation and recombination in depletion region
- Ideal pn junction current
- charge carrier transport: forward bias

Hole diffusion: 
$$J_p(x_n) = -eD_p \frac{dp_n(x)}{dx}\Big|_{x=x_n}$$

Assume uniformly doped:

$$J_p(x_n) = -eD_p \frac{d(\delta p_n(x))}{dx} \bigg|_{x=x_n}$$

Remember 
$$\delta p_n(x) = p_n(x) - p_{n0} = p_{n0} \left[ \exp\left(\frac{eV_a}{kT}\right) - 1 \right] \exp\left(\frac{x_n - x}{L_p}\right)$$



Take the derivative of  $\delta p_n(x)$ 

$$J_p(x_n) = \frac{eD_p p_{n0}}{L_p} \left[ \exp\left(\frac{eV_a}{kT}\right) - 1 \right]$$

Current direction: p to n

- <u>Assumption: No generation and recombination in depletion region</u>
- Ideal pn junction current

charge carrier transport: forward bias

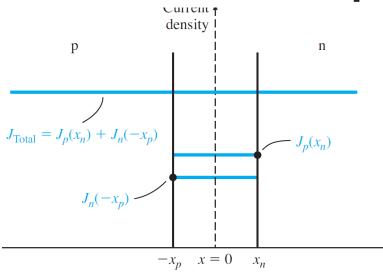
Similarly, electron diffusion: 
$$J_n(-x_p) = eD_n \left. \frac{d(\delta n_p(x))}{dx} \right|_{x=-x_p}$$

Current direction: also p to n, add together! 
$$\frac{J_n}{J_p} = \frac{D_n n_{p0}/L_n}{D_p p_{n0}/L_p}$$

Total diffusion: ideal L V relationship of a pp junction

Total diffusion: ideal I-V relationship of a pn junction

$$J = J_p(x_n) + J_n(-x_p) = \left[\frac{eD_p p_{n0}}{L_p} + \frac{eD_n n_{p0}}{L_n}\right] \left[\exp\left(\frac{eV_a}{kT}\right) - 1\right]$$



Define 
$$J_s = \left[ \frac{eD_p p_{n0}}{L_p} + \frac{eD_n n_{p0}}{L_n} \right]$$

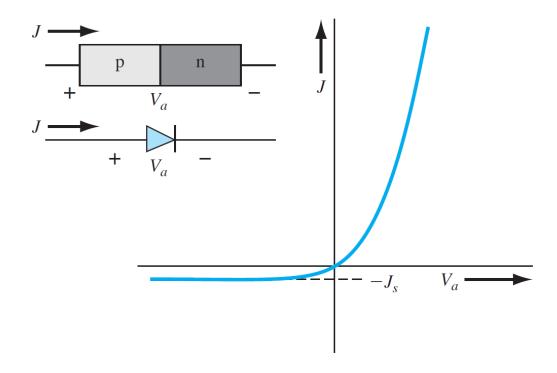
Ideal diode equation:

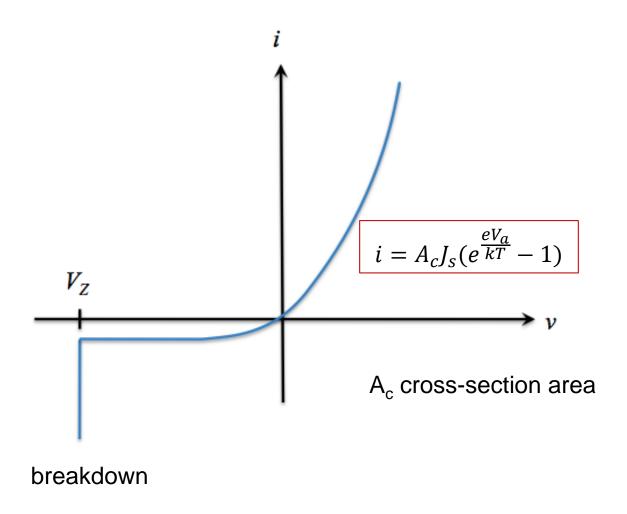
$$J = J_s \left[ \exp \left( \frac{eV_a}{kT} \right) - 1 \right]$$

 $V_a$  can be negative

- Assumption: No generation and recombination in depletion region
- Ideal pn junction current

 $J_{\rm S}$ : reverse-saturation current density





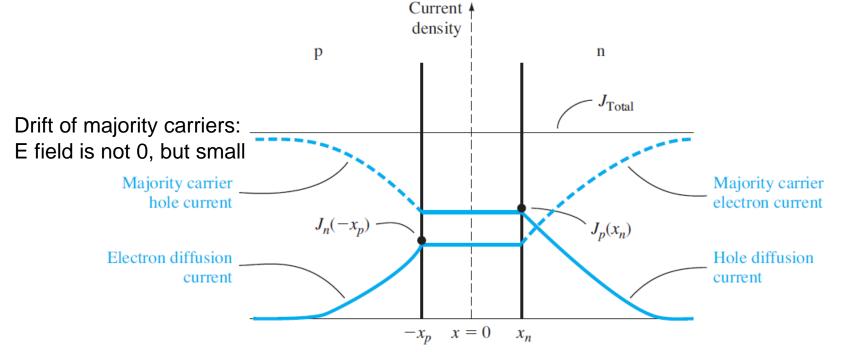
Current in p and n region: Forward bias

$$\vec{J}_p = e\vec{F}_p = -eD_p \frac{d\delta p}{dx} \vec{x} \qquad \vec{J}_n = -e\vec{F}_n = eD_n \frac{d\delta n}{dx} \vec{x}$$

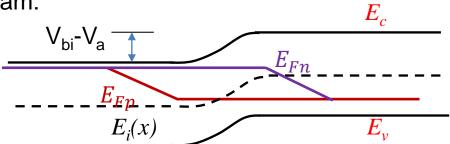
$$\vec{J}_n = -e\vec{F}_n = eD_n \frac{d\delta n}{dx}$$

$$J_p(x) = \frac{eD_p p_{n0}}{L_p} \left[ \exp\left(\frac{eV_a}{kT}\right) - 1 \right] \exp\left(\frac{x_n - x}{L_p}\right) \qquad (x \ge x_n)$$

$$J_n(x) = \frac{eD_n n_{p0}}{L_n} \left[ \exp\left(\frac{eV_a}{kT}\right) - 1 \right] \exp\left(\frac{x_p + x}{L_n}\right) \qquad (x \le -x_p)$$

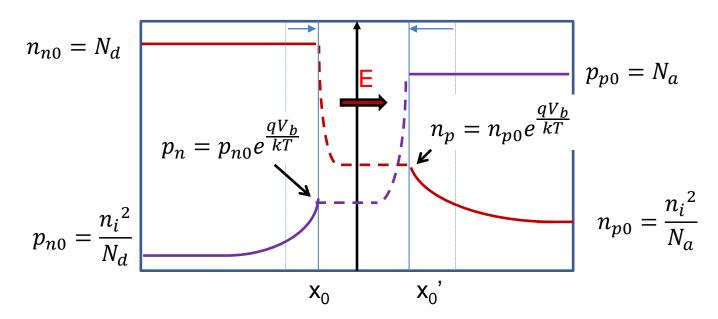


Energy diagram:



Forward bias

To understand this, see the next page.



#### Current and Fermi level

$$J_{n} = J_{diff,n} + J_{drift,n}$$

$$J_{n} = eD_{n} \frac{dn}{dx} + ne\mu_{n}|E|$$

$$= kT\mu_{n} \frac{dn}{dx} + ne\mu_{n}|E|$$

$$= ne\mu_{n} \left(\frac{kT}{ne} \frac{dn}{dx} + |E|\right)$$

$$= ne\mu_{n} \left[\frac{kT}{e} \frac{dln(n)}{dx} + |E|\right] \qquad n = n_{i}$$

$$= ne\mu_{n} \left[\frac{dE_{F}}{edx} - \frac{dE_{i}}{edx} + |E|\right] \qquad \Rightarrow \frac{d}{dx} \ln x$$

$$J_{n} = n\mu_{n} \frac{dE_{F}}{dx} \qquad \frac{dE_{i}}{dx} = -\frac{dE_{i}}{dx} =$$

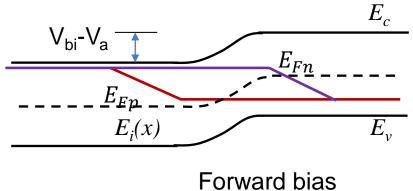
$$D_n = kT\mu_n/e$$

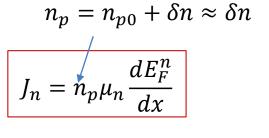
$$= ne\mu_n \left[ \frac{kT}{e} \frac{dln(n)}{dx} + |E| \right] \qquad n = n_i \exp\left( \frac{E_F - E_{Fi}}{kT} \right) \Rightarrow \ln(n) = \ln(n_i) + \frac{E_F - E_{Fi}}{kT}$$

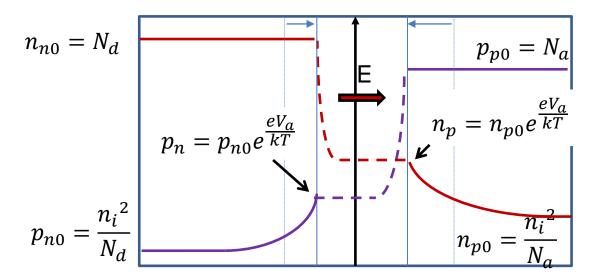
$$= ne\mu_n \left[ \frac{dE_F}{edx} - \frac{dE_i}{edx} + |E| \right] \Rightarrow \frac{d}{dx} \ln(n) = \frac{d}{dx} \left( \frac{E_F - E_{Fi}}{kT} \right) = \frac{1}{kT} \left( \frac{dE_F}{dx} - \frac{dE_i}{dx} \right)$$

$$\frac{dE_i}{dx} = -e\frac{dV(x)}{dx} = e|E|$$

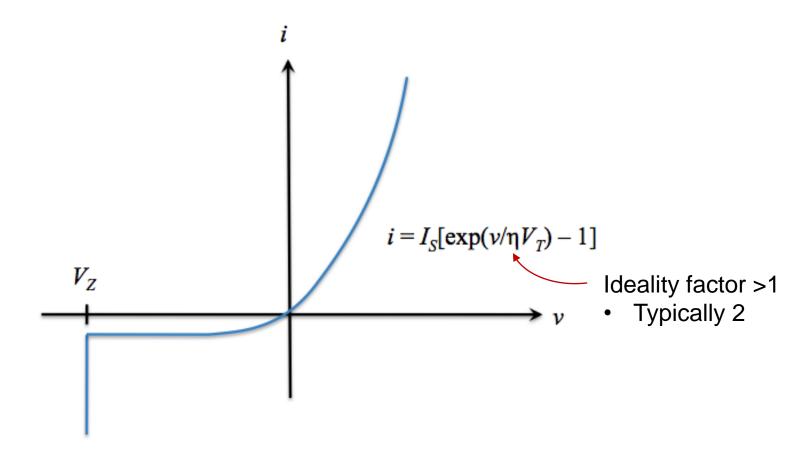
#### Energy diagram:



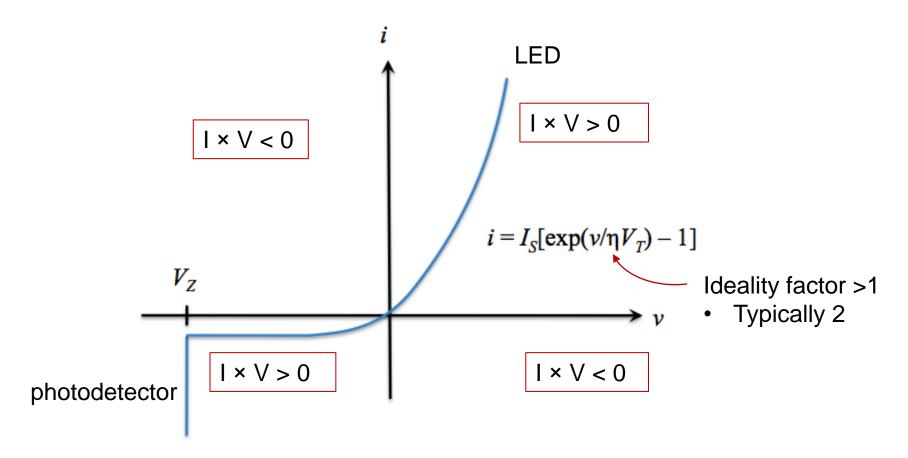




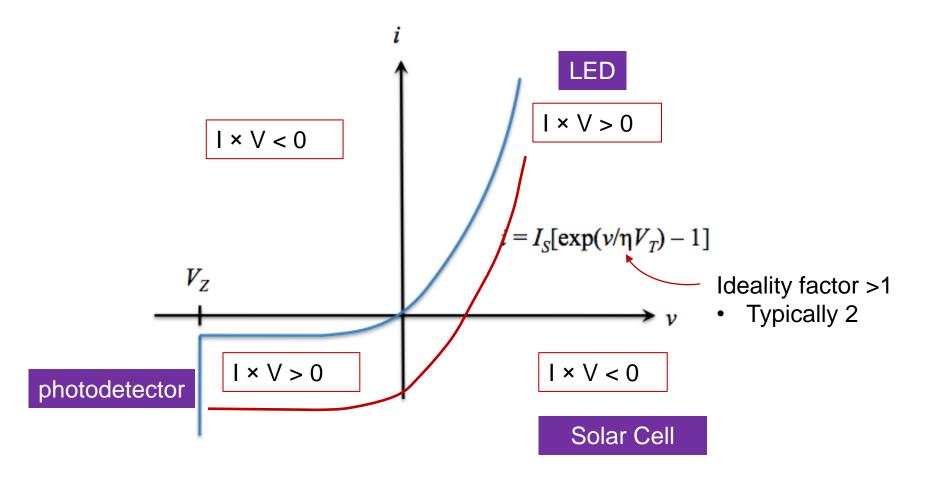
Ideality factor



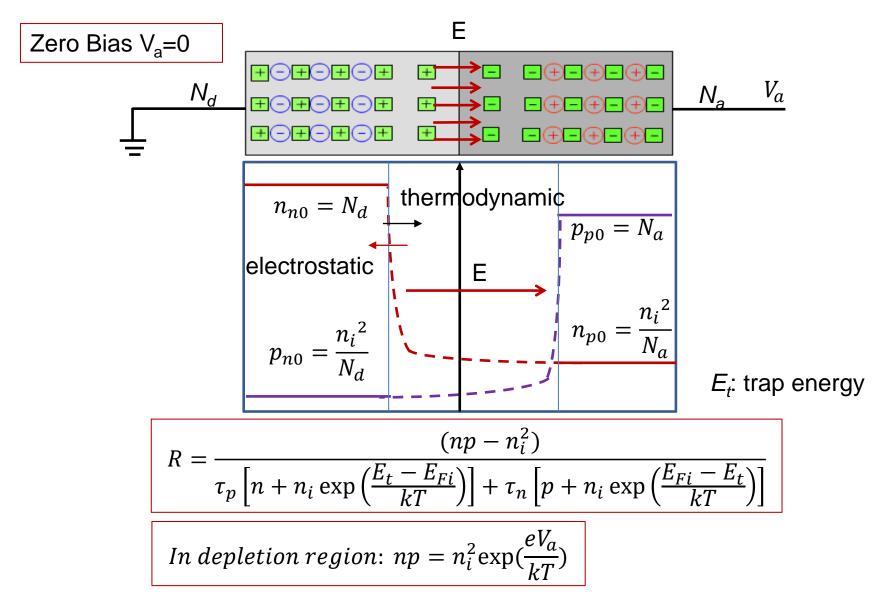
Energy consumption:

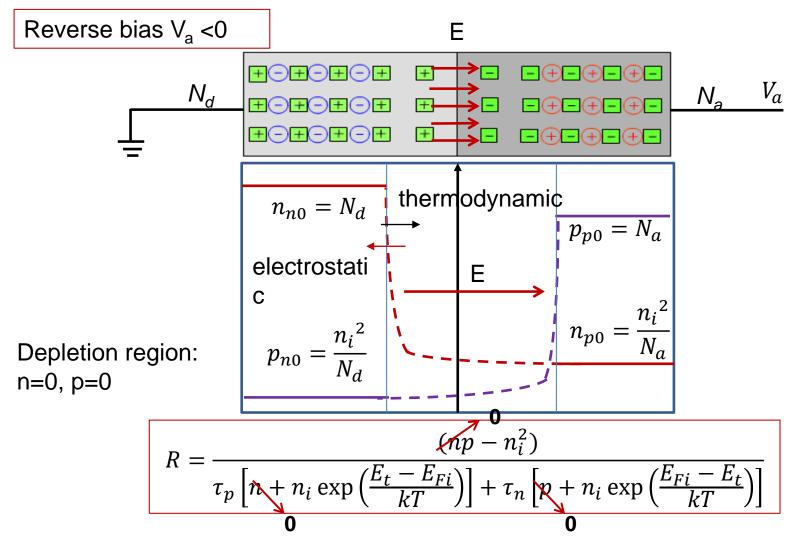


Energy consumption:

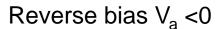


# G-R in depletion region at zero bias





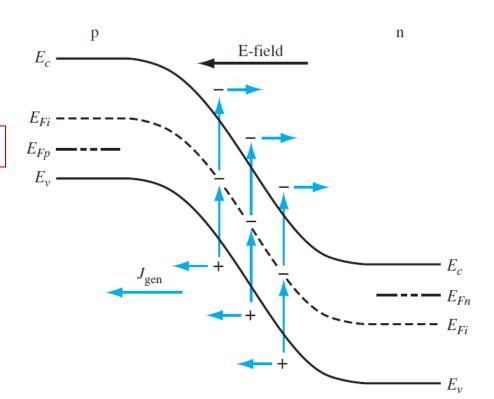
R<0: generation! Generated via the trap level



To simplify the calculation, we assume

$$E_t = E_{Fi}$$
,  $\tau_n = \tau_p = \tau$ 

$$R = \frac{-n_i}{2\tau} = -G_0$$



$$R = \frac{(np - n_i^2)}{\tau_p \left[ n + n_i \exp\left(\frac{E_t - E_{Fi}}{kT}\right) \right] + \tau_n \left[ p + n_i \exp\left(\frac{E_{Fi} - E_t}{kT}\right) \right]}$$

$$\mathbf{0}$$

Reverse bias  $V_a < 0$ 

To simplify the calculation, we assume

$$E_t = E_{Fi}$$
,  $\tau_n = \tau_p = \tau$ 

$$R = \frac{-n_i}{2\tau} = -G_0$$

Reverse-biased generation current, in addition to the ideal reverse-biased saturation current

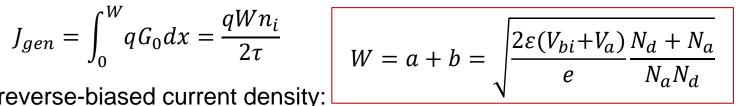
Current density from G-R in the depletion region:

$$J_{gen} = \int_0^W qG_0 dx = \frac{qWn_i}{2\tau}$$

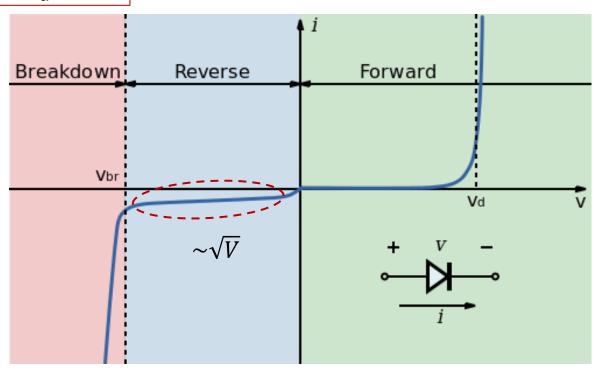
Total reverse-biased current density:

$$J_{R}=J_{s}+J_{\mathrm{gen}}$$

Dependent on the applied voltage



Reverse bias  $V_a < 0$ 

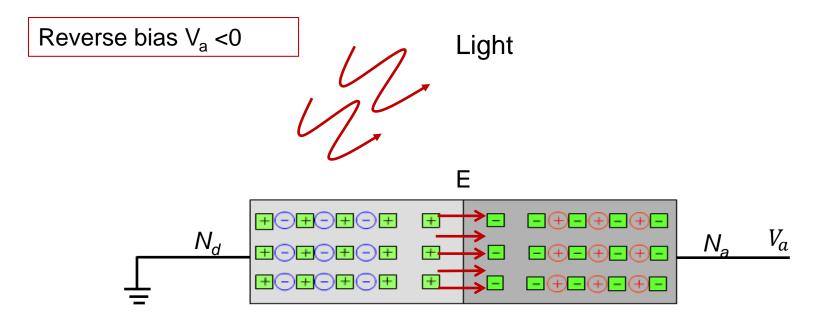


Current density from G-R in the depletion region:

$$J_r = \int_0^W eGdx = \frac{eWn_i}{2\tau}$$

$$W = a + b = \sqrt{\frac{2\varepsilon(V_{bi} + V_a)}{e} \frac{N_d + N_a}{N_a N_d}}$$

#### Photocurrent at Reverse Bias

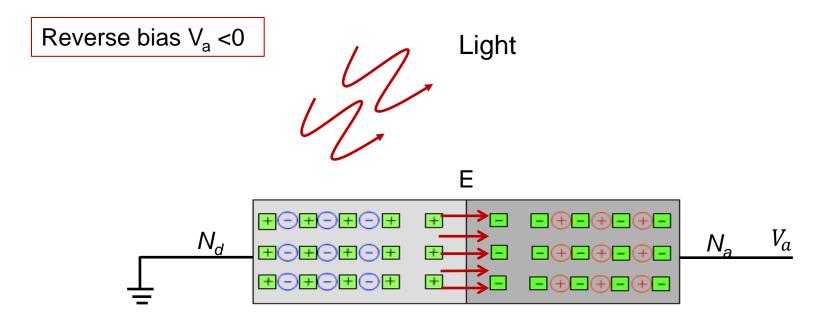


Generation: Gex

net recombination: 
$$R - G = R - (G_0 + G_{ex}) = -G_0 - G_{ex}$$

n=0 and p=0 → Recombination in the depletion is zero

#### Photocurrent at Reverse Bias

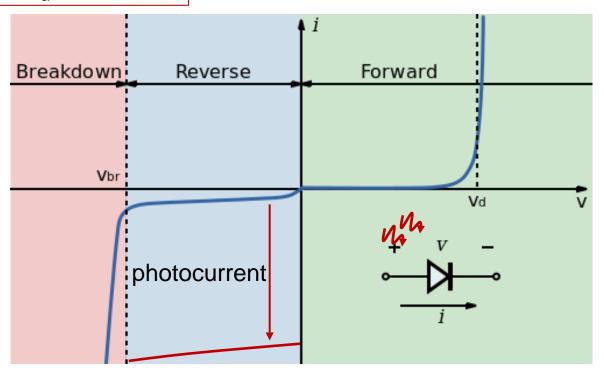


Generation: Gex

$$J_{r,ph} = \int_0^W e(G_0 + G_{ex}) dx = e(G_0 + G_{ex}) W$$

#### Photocurrent at Reverse Bias

#### Reverse bias V<sub>a</sub> <0



$$J_{r,ph} = \int_0^W e(G_0 + G_{ex}) dx = e(G_0 + G_{ex}) W$$

Forward bias V<sub>a</sub> >0

$$R = \frac{(np - n_i^2)}{\tau_p \left[ n + n_i \exp\left(\frac{E_t - E_{Fi}}{kT}\right) \right] + \tau_n \left[ p + n_i \exp\left(\frac{E_{Fi} - E_t}{kT}\right) \right]}$$

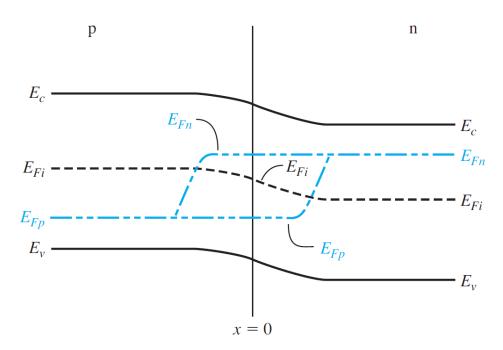
In depletion region:  $np = n_i^2 \exp(\frac{eV_a}{kT})$ 

To simplify the calculation, we assume

$$E_t = E_i$$
,  $\tau_n = \tau_p = \tau$ 

$$R = \frac{np - n_i^2}{\tau(n + p + 2n_i)}$$

Max: n=p



$$R = \frac{(np - n_i^2)}{\tau_p \left[ n + n_i \exp\left(\frac{E_t - E_{Fi}}{kT}\right) \right] + \tau_n \left[ p + n_i \exp\left(\frac{E_{Fi} - E_t}{kT}\right) \right]}$$

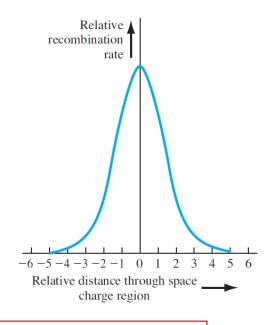
In depletion region:  $np = n_i^2 \exp(\frac{eV_a}{kT})$ 

To simplify the calculation, we assume

$$E_t = E_i$$
,  $\tau_n = \tau_p = \tau$ 

$$R = \frac{np - n_i^2}{\tau(n + p + 2n_i)}$$

Max: n=p, center of space charge region



$$R_{max} = \frac{np - n_i^2}{\tau \left[ n_i \exp(\frac{eV_a}{2kT}) + n_i \exp(\frac{eV_a}{2kT}) + 2n_i \right]} = \frac{n_i \left[ \exp\left(\frac{eV_a}{kT}\right) - 1 \right]}{2\tau \left[ \exp\left(\frac{eV_a}{2kT}\right) + 1 \right]}$$

$$R_{max} = \frac{np - n_i^2}{\tau \left[ n_i \exp(\frac{eV_a}{2kT}) + n_i \exp(\frac{eV_a}{2kT}) + 2n_i \right]} = \frac{n_i \left[ \exp\left(\frac{eV_a}{kT}\right) - 1 \right]}{2\tau \left[ \exp\left(\frac{eV_a}{2kT}\right) + 1 \right]}$$

Assume  $V_a >> kT/e$ 

$$R_{max} = \frac{n_i}{2\tau} \exp\left(\frac{eV_a}{2kT}\right)$$

$$R_{max} = \frac{n_i}{2\tau} \exp\left(\frac{eV_a}{2kT}\right)$$

Current density from G-R in the depletion region:

$$J_r = \int_0^W eR dx = \frac{eW n_i}{2\tau} \exp\left(\frac{eV_a}{2kT}\right)$$
 Assume maximum recombination rate is effective 
$$J_r = J_{r0} \exp\left(\frac{eV_a}{2kT}\right)$$

For a non-ideal pn junction, the total current density:

$$J = J_F + J_r = J_s \exp\left(\frac{eV_a}{kT}\right) + \frac{eWn_i}{2\tau} \exp\left(\frac{eV_a}{2kT}\right)$$

#### Non-ideal IV curves

Forward bias V> 3kT/e=0.078V:

$$J = J_F + J_r = J_S \exp\left(\frac{eV_a}{kT}\right) + \frac{eWn_i}{2\tau} \exp\left(\frac{eV_a}{2kT}\right)$$

At a low current density, the recombination current dominates, and at a higher current density, the ideal diffusion current dominates

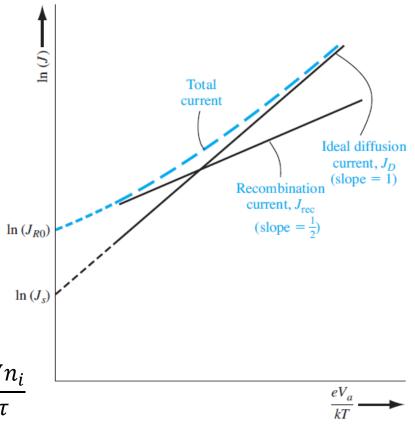
Diode *I-V* relationship:

$$I = I_s \left[ \exp\left(\frac{eV_a}{nkT}\right) - 1 \right]$$

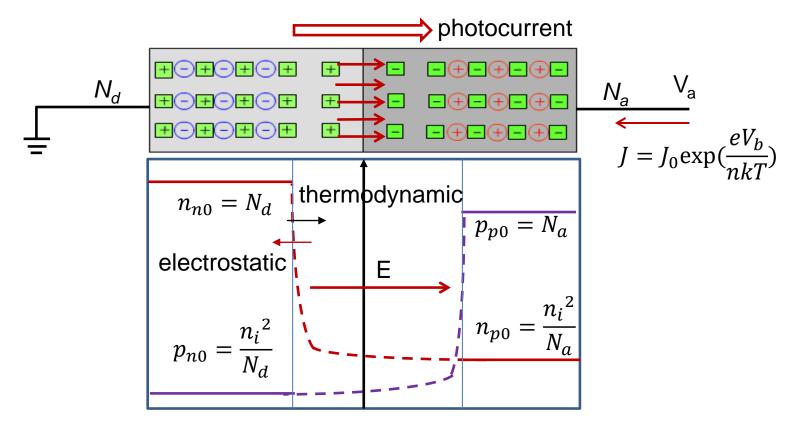
the ideality factor

Reverse bias:

$$J = -J_s - \frac{eWn_i}{2\tau} = -\left(\frac{eD_nn_{p0}}{L_n} + \frac{eD_pp_{n0}}{L_p}\right) - \frac{eWn_i}{2\tau}$$



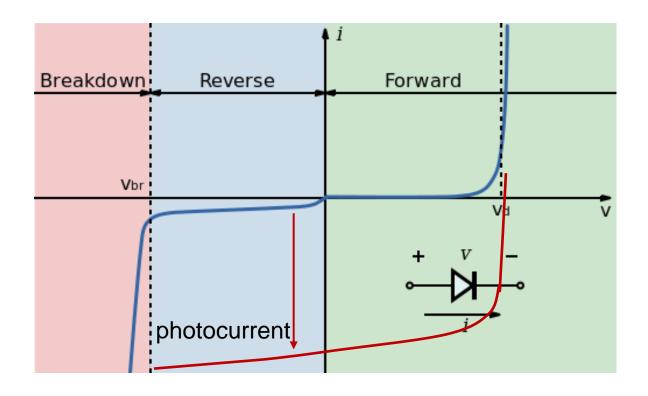
#### IV curve under illumination



Net current density:

$$J_{net} = J - J_{ph} = J_0 \exp\left(\frac{eV_a}{nkT}\right) - eG_{ex}W$$

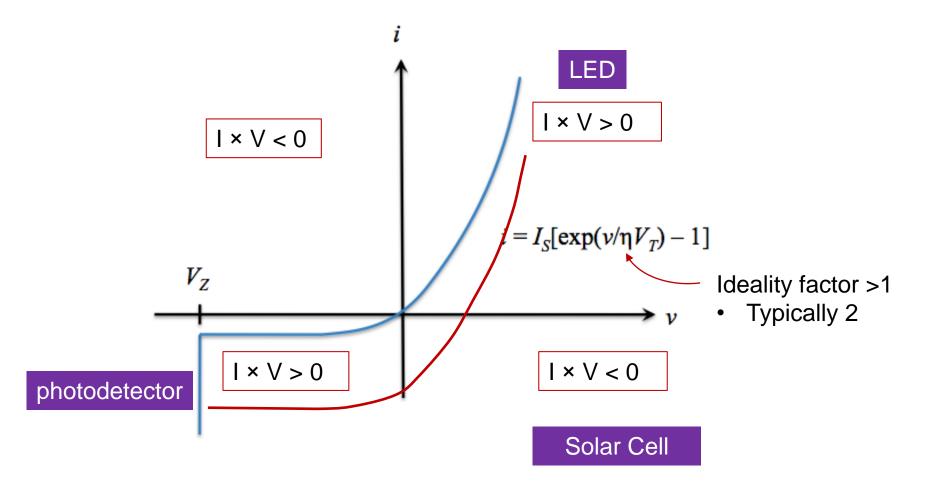
#### IV curve under illumination



Net current density:

$$J_{net} = J - J_{ph} = J_0 \exp\left(\frac{eV_a}{nkT}\right) - eG_{ex}W$$

Energy consumption:



# High-level injection

$$np = n_i^2 \exp\left(\frac{V_a}{V_t}\right)$$

Excess carrier concentrations become comparable or even greater than the majority carrier concentration  $\delta n > n_o$  and  $\delta p > p_o$ 

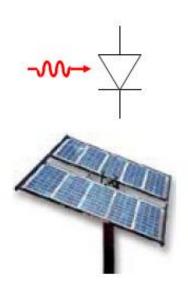
$$(\delta n)(\delta p) \cong n_i^2 \exp\left(\frac{V_a}{V_t}\right)$$

$$\delta n = \delta p \cong n_i \exp\left(\frac{V_a}{2V_t}\right)$$

$$I \propto \exp\left(\frac{V_a}{2V_t}\right)$$

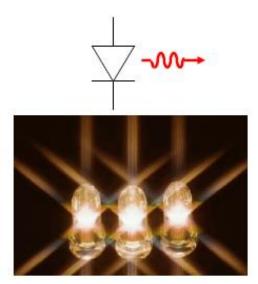
# Semiconductor Optoelectronic Diodes

Detectors convert optical signals into electrical signals



- Photodetectors: primary purpose to detect photons
- Solar Cells: primary purpose is photo-to-electrical energy conversion

Emitters are a source of optical radiation



- Light-emitting diodes (LEDs)
- Lasers –may be obtained using optical cavity

